

Title:	Performance report for SiT3372, 148.351648 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

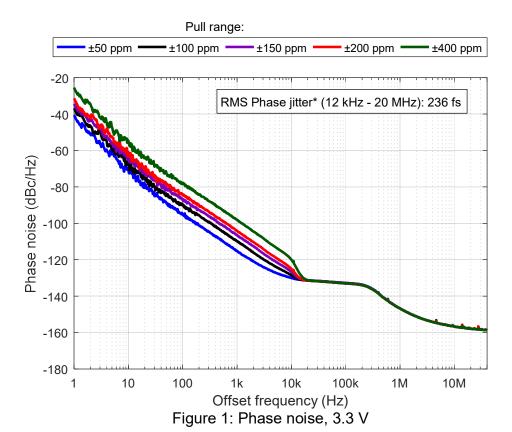
Performance report for SiT3372 - 148.351648 MHz, HCSL

This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



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*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz					
Frequency offset	Pull range (ppm)				
(Hz)	±50	±100	±150	±200	±400
1	-40.6	-36.8	-34.4	-31.3	-25.5
10	-69.9	-68.1	-65.2	-60.9	-54.8
100	-94.8	-90.1	-86.6	-84.0	-77.8
1 K	-115.3	-109.9	-106.4	-104.2	-98.0
10 K	-130.0	-128.6	-126.7	-125.1	-120.0
100 K	-132.8	-133.0	-132.8	-133.1	-133.0
1 M	-146.7	-146.8	-146.7	-146.7	-146.8
10 M	-156.7	-156.7	-156.7	-156.7	-156.7
40 M	-158.6	-158.6	-158.6	-158.6	-158.6

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Table 2: Integrated Phase jitter

Parameter	Units	Pull range (ppm)	
Parameter	UTIILS	±50 to ±400	
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	102	
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	236	



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Figure 2: Output waveform, 2.5 V

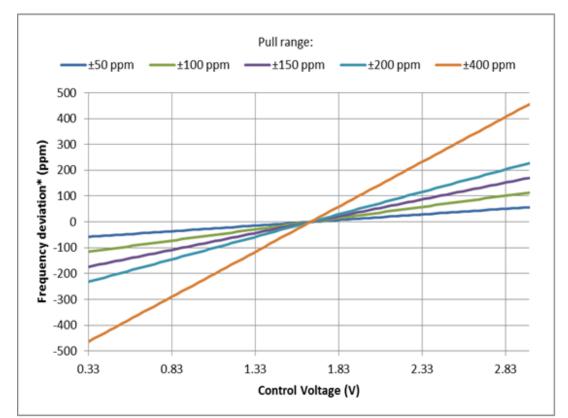


Figure 3: Output waveform, 3.3 V

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Figure 4: Frequency pull characteristic



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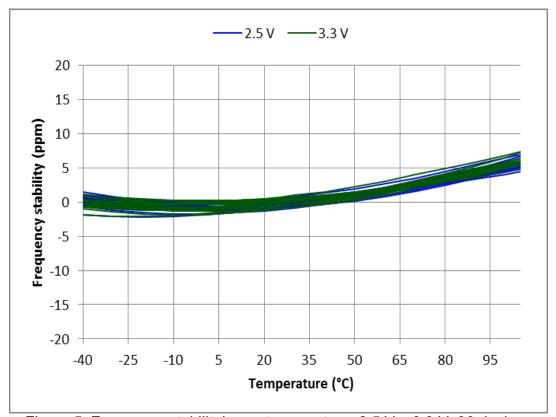


Figure 5: Frequency stability* over temperature, 2.5 V – 3.3 V, 30 devices

*SiT3372 frequency stability is independent of output frequency.



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Table 3: Summary performance data

Parameter	Units	Voltage	
Parameter	Utilts	2.5 V	3.3 V
Period jitter	ps, rms	1.07	1.05
Period jitter (sample size 10,000 cycles)	ps, pk-pk	8.15	7.99
Duty cycle	%	50.1	50.1
Rise time (20% - 80%)	ps	375	372
Fall time (80% - 20%)	ps	376	374
Differential voltage swing	V	1.46	1.52
Current consumption (no load, output enabled)	mA	83.5	84.1
Current consumption (no load, output disabled)	mA	57.0	57.2



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Test description

Conditions:

- Frequency: 148.351648 MHz

- VDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

Equipment:

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



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Setup

Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 30 Ω series and 50 Ω to GND. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

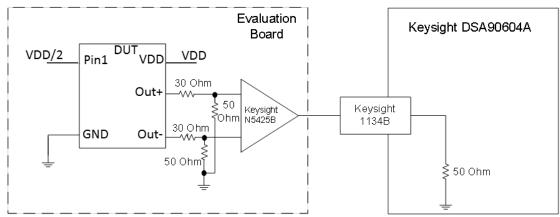


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

Period Jitter

For period jitter measurement output is terminated with 30 Ω series and 50 Ω to GND at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 7 shows test setup diagram for period jitter measurement.

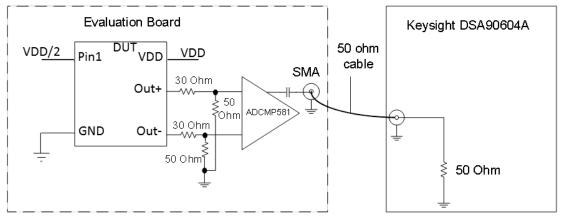


Figure 7. Test setup for measuring period jitter

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Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Output is also terminated with 30 Ω series at the source side. Figure 8 shows test setup diagram for phase noise measurement.

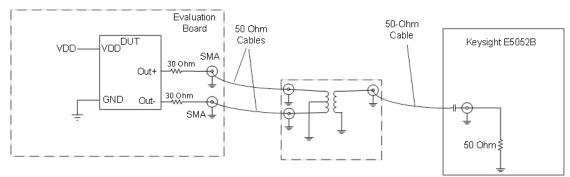


Figure 8. Test setup for measuring phase noise.

Current consumption

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.